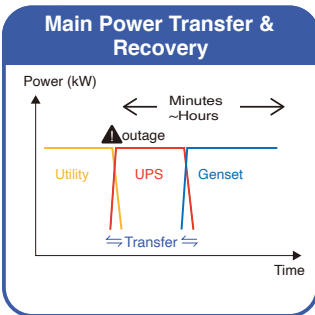
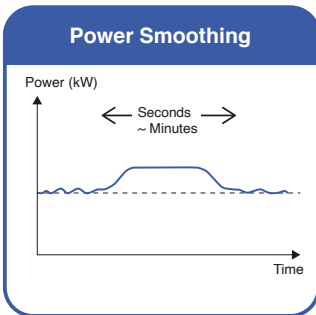
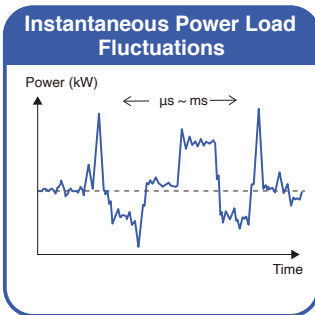
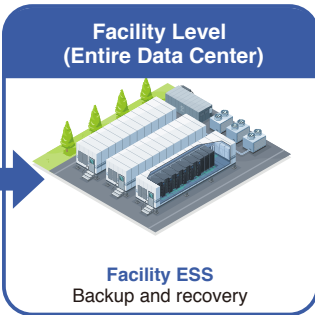
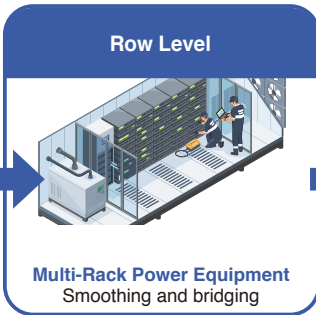
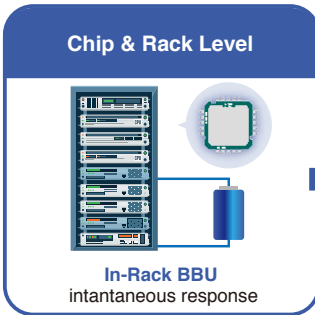


BBU Load Variation Test Solution



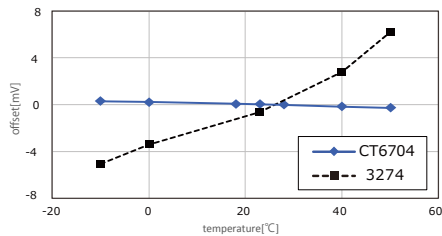
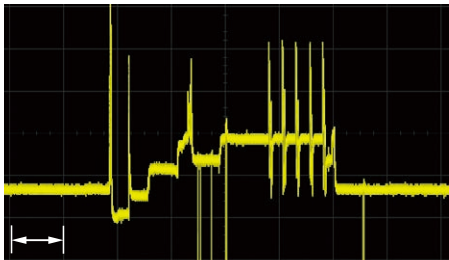
AI data center power stabilization spans multiple time scales.



Each layer supports a different role, from fast load response to long-duration backup.

Key Requirements for BBU Power Evaluation

For data center power validation, recorders must capture fast transients, maintain waveform stability during long-term observation, and simplify multi-channel measurement setup.



Capture fast transient events

Fast transient events happen in an instant, so continuous recording is essential to avoid missing brief current changes during BBU load validation.

Stable current waveform observation

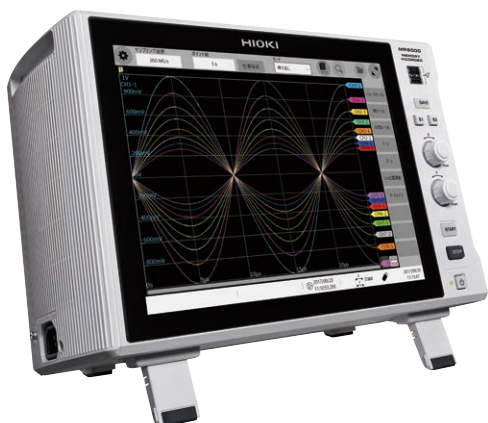
Probe thermal drift can reduce confidence in long-term waveform evaluation. Low-drift current probes help maintain stable observation over time.

Simplify multi-channel measurement setup

Powering current probes and differential probes from the main unit simplifies wiring and reduces overall setup time.

BBU Load Variation Test Solution

- For high-speed transient capture, stable long-term measurement, and multi-channel setup -



A complete solution for fast transient capture and stable long-term current observation

We offer a lineup ranging from clamp current sensors capable of handling up to 2000 A to wide-band current probes, enabling highly reliable, low-drift measurements tailored to the targets of data center power supply evaluation.



CT6704/CT6705
Faithfully observe high-speed transient responses.



CT6846A/CT6847A
Stable measurement of large currents.

Recommended System Configuration

Practical configuration example combining recorders, current probes, power units, and related options



MR6000-01
MEMORY HICODER
(real-time waveform calculation)



U8975
4CH ANALOG UNIT
(Bandwidth: DC to 2 MHz)



U8977
3CH CURRENT UNIT
Bandwidth: DC to 2 MHz



Z5021
PROBE POWER UNIT
(Up to 5 CT6704, CT6705 can be connected)



U8335
SSD UNIT
(Built-in type 1TB storage)



CT6704
CURRENT PROBE
(DC to 30 MHz, 200 A)



CT6705
CURRENT PROBE
(DC to 15 MHz, 500 A)



CT6846A/CT6847A
CURRENT PROBE
(CT6846A: 1000 A AC/DC)
(CT6847A: 2000 A DC, 1400 A AC)



9322
DIFFERENTIAL PROBE
(DC to 10MHz, DC 2000 V)



9248
POWER CORD
(Power supply to 9322 using Z5021)

Key specifications

MR6000-01	Number of input units: up to 8 units, memory capacity: 1G word, number of channels: up to 32 analog channels, equipped with real-time waveform calculation and digital filter functions
U8975	4 channels, channel-to-channel isolation, sampling rate: 5 MS/s, maximum input voltage: DC 200 V, resolution: 1/32000 of range (using 16-bit A/D)
CT6704/CT6705	CT6704 [Rated current: 200 Arms, Maximum peak current: ±400 A peak, Frequency bandwidth: DC to 30 MHz] CT6705 [Rated current 500 Arms, Maximum peak current: ±800 A peak, Frequency bandwidth: DC to 15 MHz] Connected to the High Speed Analog Unit U8976.
U8977	3 channels, channel-to-channel isolation, sampling rate 5 MS/s, supplying power to current sensors, resolution 1/32000 of range (using 16-bit A/D)
CT6846A/CT6847A	CT6846A [Rated current: AC/DC 1000 A, Maximum peak current: ±1900 A peak, Frequency bandwidth: DC to 100 kHz] CT6847A [Rated current: DC 1000 A, AC 1400 Arms, Maximum peak current: ±2400 A peak, Frequency bandwidth: DC to 70 kHz] Connected to the 3CH Current Unit U8977.
9322	Input voltage: DC 2 kV, AC 1 kV, frequency bandwidth DC to 10 MHz (DC mode, for waveform monitoring), DC/AC RMS conversion: (RMS mode, frequency characteristic: DC, 40 to 100 kHz), maximum rated voltage to ground: AC, DC 1000 V (CAT II), DC amplitude accuracy: ±1% full scale (below DC 1000 V)



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